Embedded SSD
Product Challenges and Test Mitigation

Flash Memory Summit, 2015
ATP Electronics, Inc.
Overview

- Embedded SSD Product Challenges
  - The Factor of Industry Focus & Validation Challenges
  - The Factor of Memory Transition
- Embedded SSD Mitigation
  - Full Scale Testing – Product Development
  - Full Scale Testing – Mass Production
The Factor of Industry Focus & Validation Challenges

- NAND Industry Focus
  - Trend Controller / NAND Design:
    - Higher ECC requirements and other NAND controller requirements such as data randomization and Read Retry/Recovery Functions
    - Focus on maximizing endurance/cycling
  - Trend / SSD Level:
    - The cost advantages of die shrink with progressively higher densities to maintain ASP
    - Focus on enterprise and client usage models
• Less attention to ....
  • Escalation of validation costs on newer process node
    – Change of reliability characteristics -> wider test coverage due to added variables, larger sample size, longer testing periods, attention to lower industry attention areas, especially data retention
    – Maintained production level screening system for DPM stability
The Factor of Memory Transition

- Reduce Endurance and Increase ECC requirement
The Factor of Memory Transition

- Indispensable Read Retry Function

![Graph showing the impact of ECC setting on later bad block numbers with options for enable and disable read retry]
Technology Migration and Consistency in Performance

- Page/Block Sizes
  (Average 16K/page MLC)

- Larger Density Per Die
  (128Gbit Mainstream)

- (Average 2.5” SSD Density)
Technology Migration and Consistency in Performance

Fewer Die Per Same Density SSD

20nm 32GB Embedded SSD

16nm 32GB Embedded SSD

Santa Clara, CA
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Technology Migration and Consistency in Performance

Embedded SSD Tendencies

Typically Smaller Density Requirements

Often Smaller file sizes data transfers

Workload Tendencies Toward Random Write
Technology Migration and Consistency in Performance

- Typically Smaller Density Requirements
- Often Smaller file sizes data transfers
- Workload Tendencies Toward Random Write

Risk of Higher WAI and Endurance Issues

Risk of Performance Erosion
Risk of Power Failure

Level 0
No Concern

- Lost Unsaved data

Level 1
How Important is Your Saved Data?

- Lost Unsaved & Saved data

Level 02,03
Fatal/ Lost All Data or Drive not recognized

- Lost File Allocation Table
- Disk cannot be found

Power (V)

Time (ms)

Power outage
Technology Migration and Consistency in Performance

- **Mitigation on Product**
  - **Overprovisioning**
    - Maintained user space with larger on board NAND usage
  - **Multi-plane NAND**
    - 2 plane and now 4 plane organized NAND
  - **Utilization of controller cache**
    - Firmware optimized per usage model
  - **Firmware optimization by usage model**
    - Auto-scan, auto-refresh, early refresh algorithms in addition to traditional wear leveling
Embedded SSD Mitigation: Test Area Deep Dives

IC/SSD Validation

- Ensuring the reliability & function of new NAND die + SSD

Mass Production

- Screening out defects & assuring complete reliability at scale
Mitigation: Full Scale Testing (SSD Validation)

- IC Level Test, Confirmed at SSD Level
  - Reliability characteristics (Endurance, Read Disturb, Data Retention) over *wide temperatures*, *and Cross temperature*
  - Set up spec, criteria and features for SSDs
Mitigation: Full Scale Testing (SSD Validation)

- SSD Level Test (1)
  - Performance: Lower/middle densities and a lower CE count for embedded/industrial application SSDs.
  - Endurance: NAND trending continues towards larger page size (8K/16K) and embedded/Industrial usage models are often utilizing much smaller file transfers. This can result in a very different write amplification factor which affects the endurance of the SSD.
Mitigation: Full Scale Testing (SSD Validation)

- SSD Level Test (2)
  - Power Fail Factors
    - Stand-alone HW solution, Industrial grade capacitors w/o degradation or flammability concern
  - Power Cycling RDT
    - Sudden, targeted power-off in write/erase operations
    - Multiple test patterns & Random power off delay timing
  - Power On/Off Test
    - Simulate sudden power off in read operations (OS boot-up application)
Mitigation: Full Scale Testing (Mass Production)

- Reliable and scalable MP validation
  - Proper production level screening mechanisms to ensure quality

Challenges
- Trade off between SSD production burn in time versus operational efficiency
- Variance of NAND RBER (Raw Bit Error Rate) and ELFR (Early Life Failure Rate) as process matures
- Variance in the same factors by wafer production lot / date code
Mitigation: Full Scale Testing (Mass Production)

- Mitigation: Efficiency in Test
  - Capability to utilize intelligent production level test based on NAND characteristics rather than pure brute force copy/compare

Example: ATP RBER factor Burn In

NAND FLASH \[\text{Error Bit Threshold e.g. 30bits}\] Controller

ECC > 30bits

Weak blocks will be marked as bad blocks when exceeding pre-set ECC threshold
Mitigation: Full Scale Testing (Mass Production)

- Mitigation: Efficiency in Test
  - Capability to utilize acceleration factor of temperature during burn in
  - Experience building to further optimize test over volume and process mature

**Higher Temperature: Burn in Acceleration Factor**

**Temperature Cycling: Production/Assembly Quality**